

### Selected Enhanced Fidelity AIM Methods

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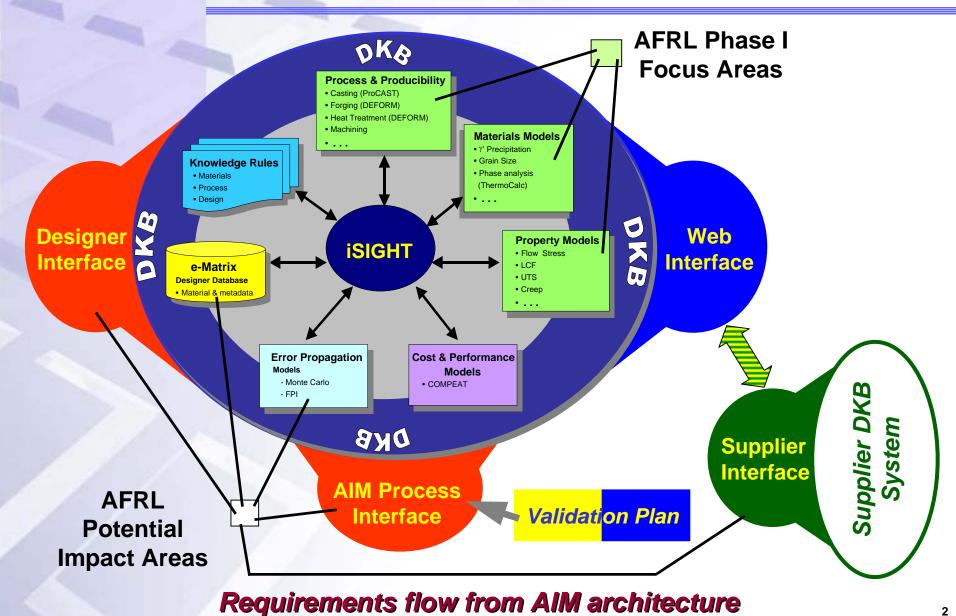
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## AIM System Architecture





#### What About Phase II & Beyond?

In general, demand is for methods to treat unknown (without database)

Numerical descriptions needed for scope & fidelity in performance prediction (property minima & fracture are locally dominated)

These require development and adaptation to system architecture

#### Thus AFRL Focus:

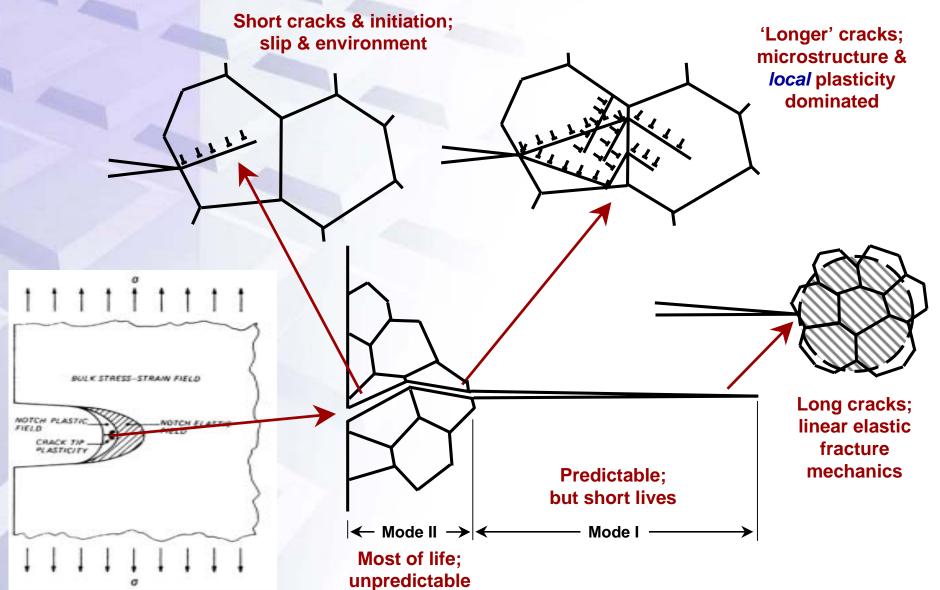
Prediction, quantification & representations of structure evolution & kinetics

Structure-sensitive numeric descriptions of properties

Overlay of 'homogenized' or 'fast-acting' models, validation/tuning procedures, & interlace with design/architecture

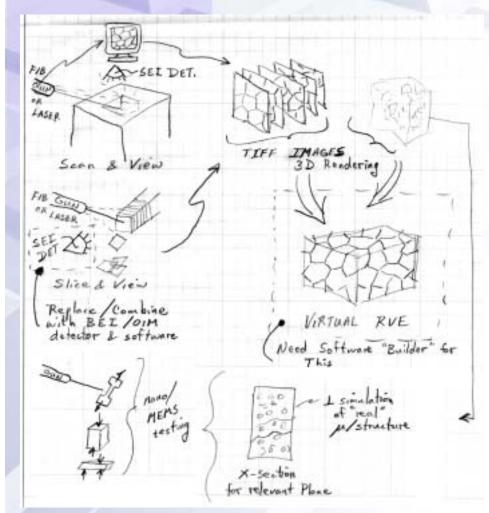


### Need for Microstructure-Based Plasticity





#### From Concepts to Realities



Last year's 'sketchy' concept

#### Briefings on Today's Progress

Phase Field (Simmons, 20min)

Plasticity Modeling (Parthasarathy, 20min)

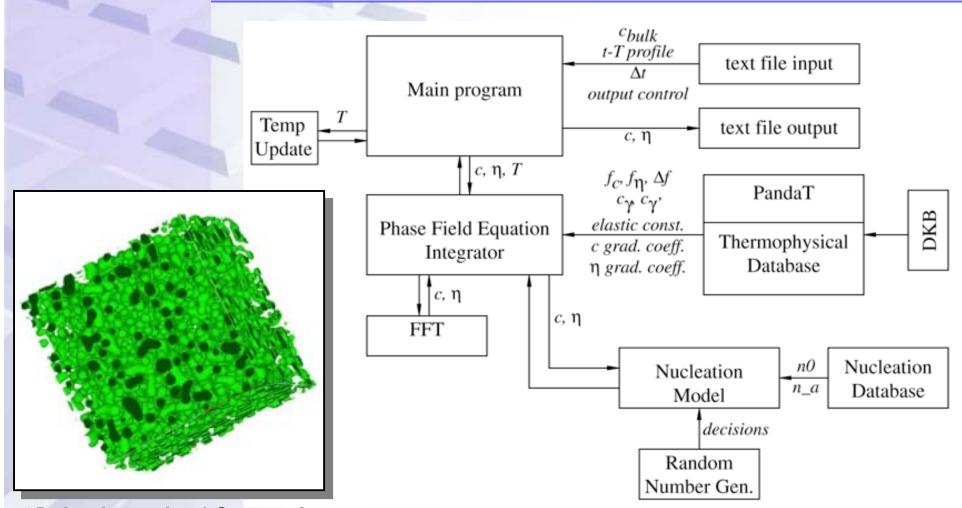
**Advanced Experimental Methods** 

- 3D Quantification (Uchic, 10min)
- Representation (Simmons, 15min)
- Micro- & Nano-scale Tests (Uchic, 15min)

Broader View & Discussion (Dimiduk, All)



### Architecture & Implementation of Phase Field Software

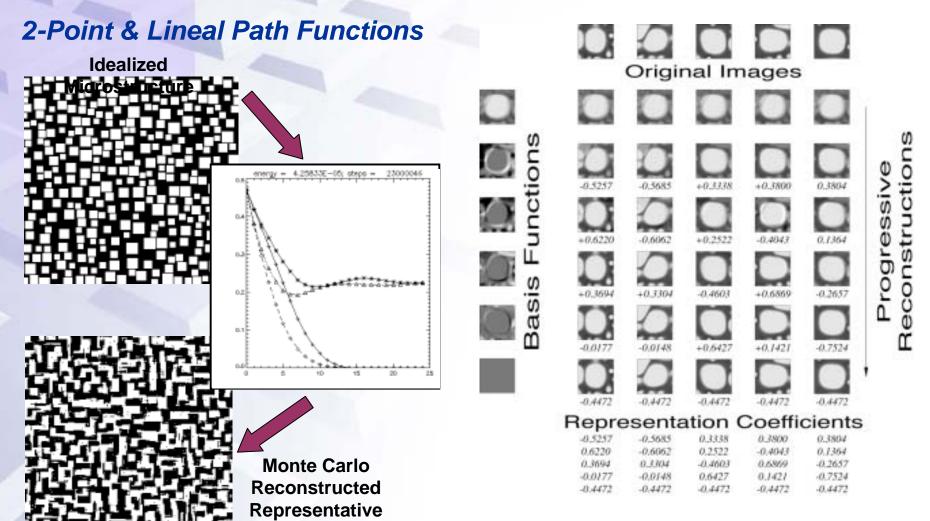


3D, Isothermal  $\gamma$ - $\gamma$ ' Coarsening

Clear framework identified...real dimensionality, thermodynamics evolving!



### Microstructure Representations



Principal Component Analysis (KLT)

Revolutionary longer-term approach to capture all information contained in microstructure

**Microstructure** 



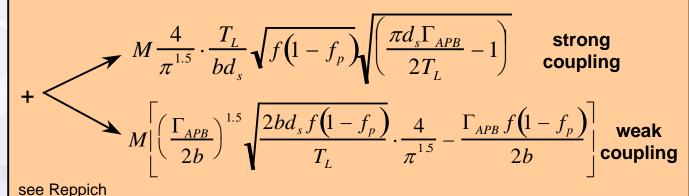
#### Beyond Analytical Strength Models

#### **Needs Development Within Atomistics**

$$\sigma_{y}(C_{i},T,\varepsilon,\dot{\varepsilon},...)=$$

$$\sigma_{y}(C_{i}, T, \varepsilon, \dot{\varepsilon}, ...) = \int_{\gamma} \left(\frac{T_{o}}{T}\right) \left(\sum_{i} \frac{dc}{\sqrt{dC_{i}}} \sqrt{C_{i}}\right) + Mf_{t}\left(\frac{\Gamma_{APB}}{b}\right)$$

#### **Obtain by Dislocation Kinetics Simulation**



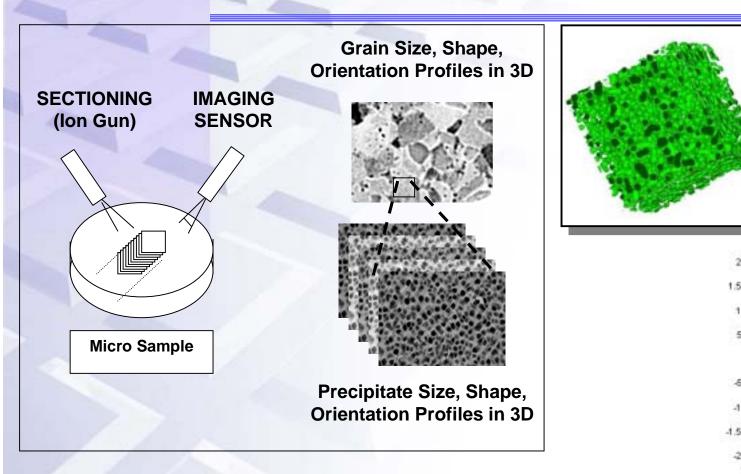
#### Obtain by FEM Simulation of Grain Distribution Effects

+ 
$$f_p \left[ \sigma(T)_{Ni_3Al} + \sum_i \left( \frac{dc}{dC_i} C_i \right) \right]$$
 +  $f_p k_y^{\gamma'} \frac{1}{\sqrt{d_{\gamma'}}}$  +  $(1 - f_p) k_y^{\gamma} \frac{1}{\sqrt{d_{\gamma'}}}$ 

Numeric methods need and interface to AIM system



#### **Unknown New Materials**



3D sectioning experiments

Advanced simulation & experiments

Image: Small-scale property measurements

The structure representations intrinsic grain-level properties

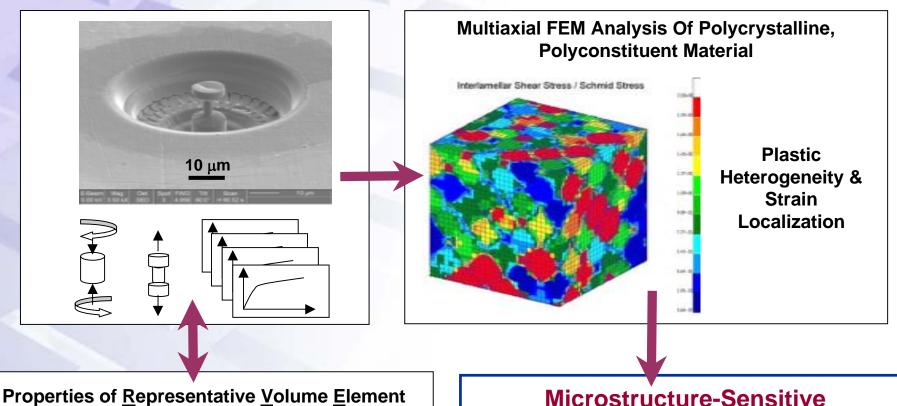
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The structure representations intrinsic grain-level properties

Dimiduk, Parthasarathy, Uchic, and Rao, 2002



#### Treating Unknown New Materials



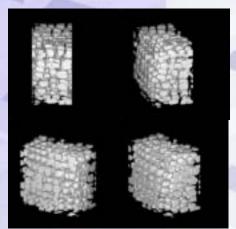
Properties of <u>Representative Volume Element</u> (RVE) From Mesoscale and Analytical Tools

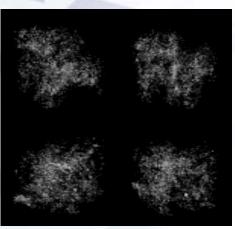
$$\dot{\tau} = \left\{ h - \left( \frac{\tau - \tau_o}{\tau_s - \tau_o} \right) h \right\} \left( \dot{\gamma} \dot{\gamma}_o \right)^m \quad \tau$$

Microstructure-Sensitive
Representations (UMATs for
'intrinsic material' RVEs; results
used in Ramberg-Osgood or Walkerlike forms, or "Curve Generator," etc)



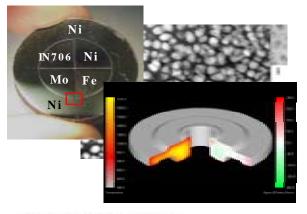
#### Efficient Experiments for New Materials

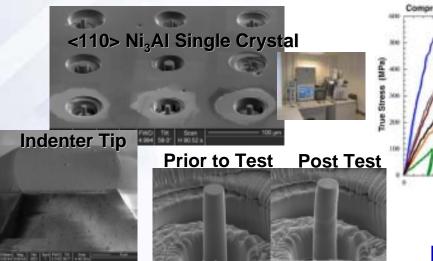


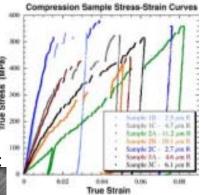


3-Dimensional Characterization of  $\gamma$  and Carbides

Rapid Experiments, Modeling, & Characterization







Micro- & Nano-Scale Property Measurement

**Unprecedented Novel & Efficient Experiments Emerging!** 



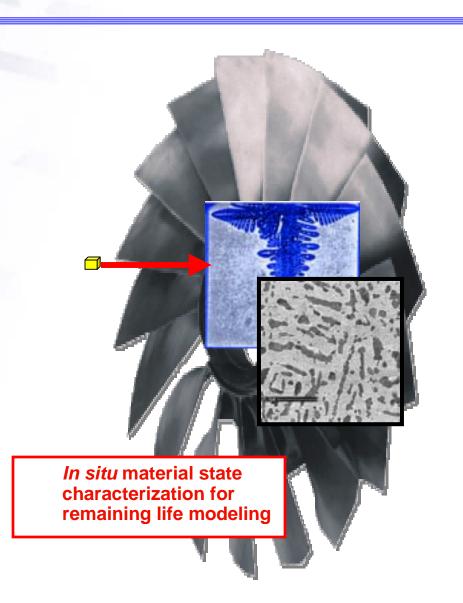
# Payoff: Materials & System Prognostics





#### **Material State Definition**

- Characterize each disk's microstructure and damage state at the mesoscale
- Utilize DARPA/AF AIM technology – stochastic life prediction
- Material state sensing
  - Electron backscatter diffraction (EBSD)
  - Acoustic attenuation
  - Others...
- Define the probability of cracking for each disk





### MS & E Paradigm

